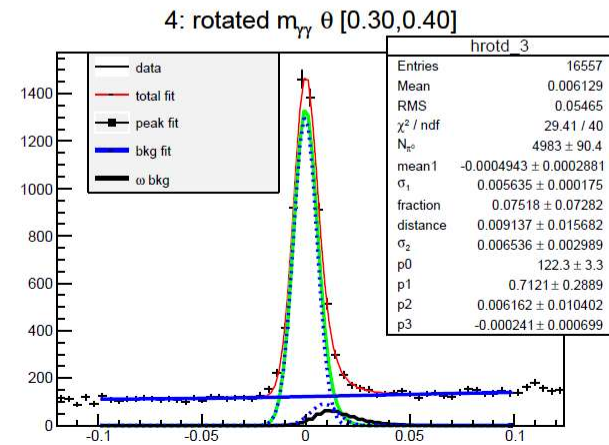
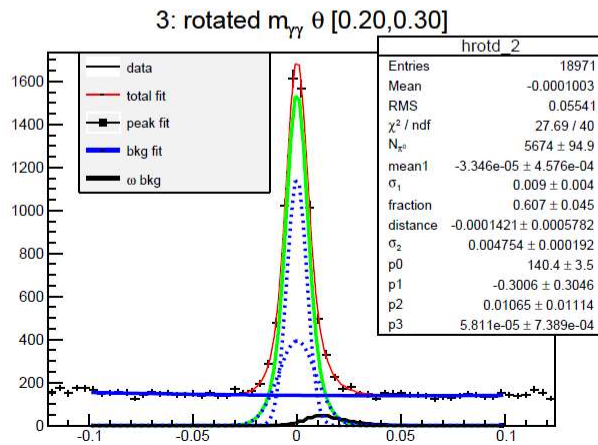
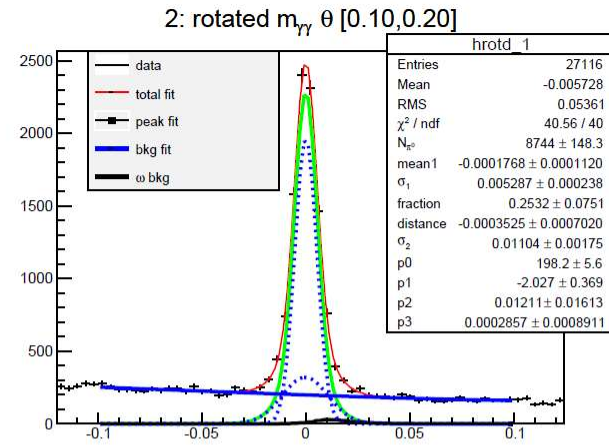
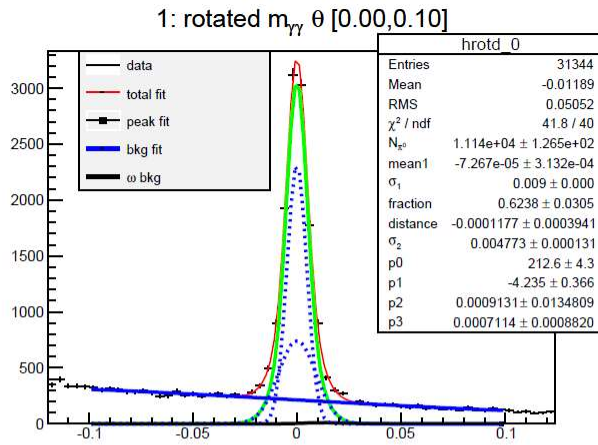


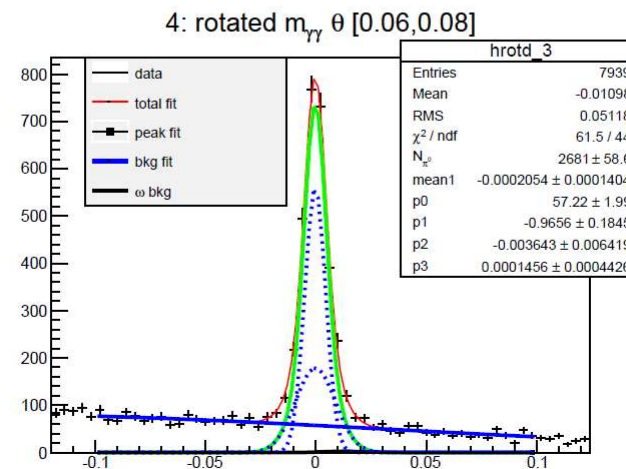
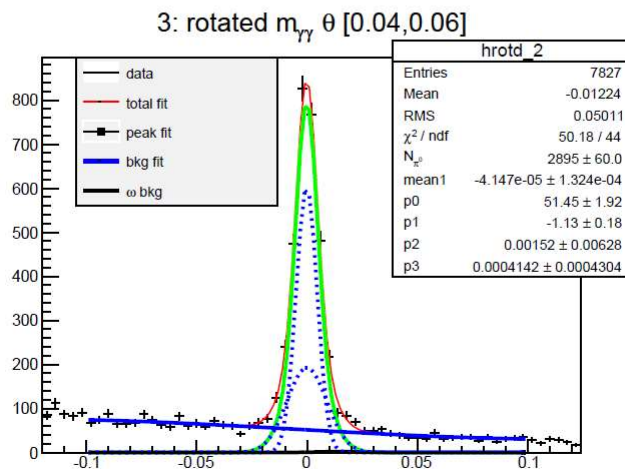
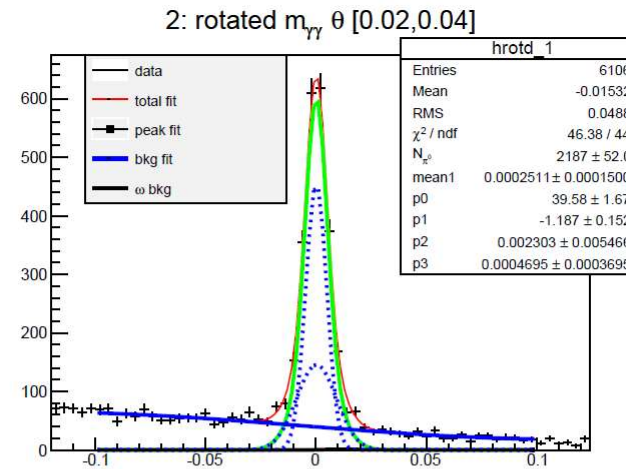
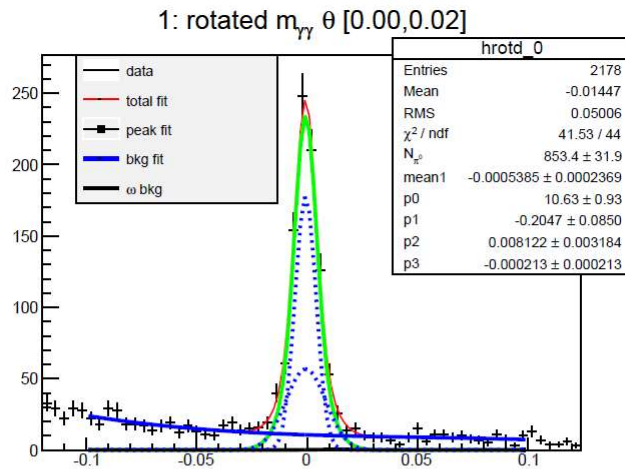
Analysis Update

Yang Zhang

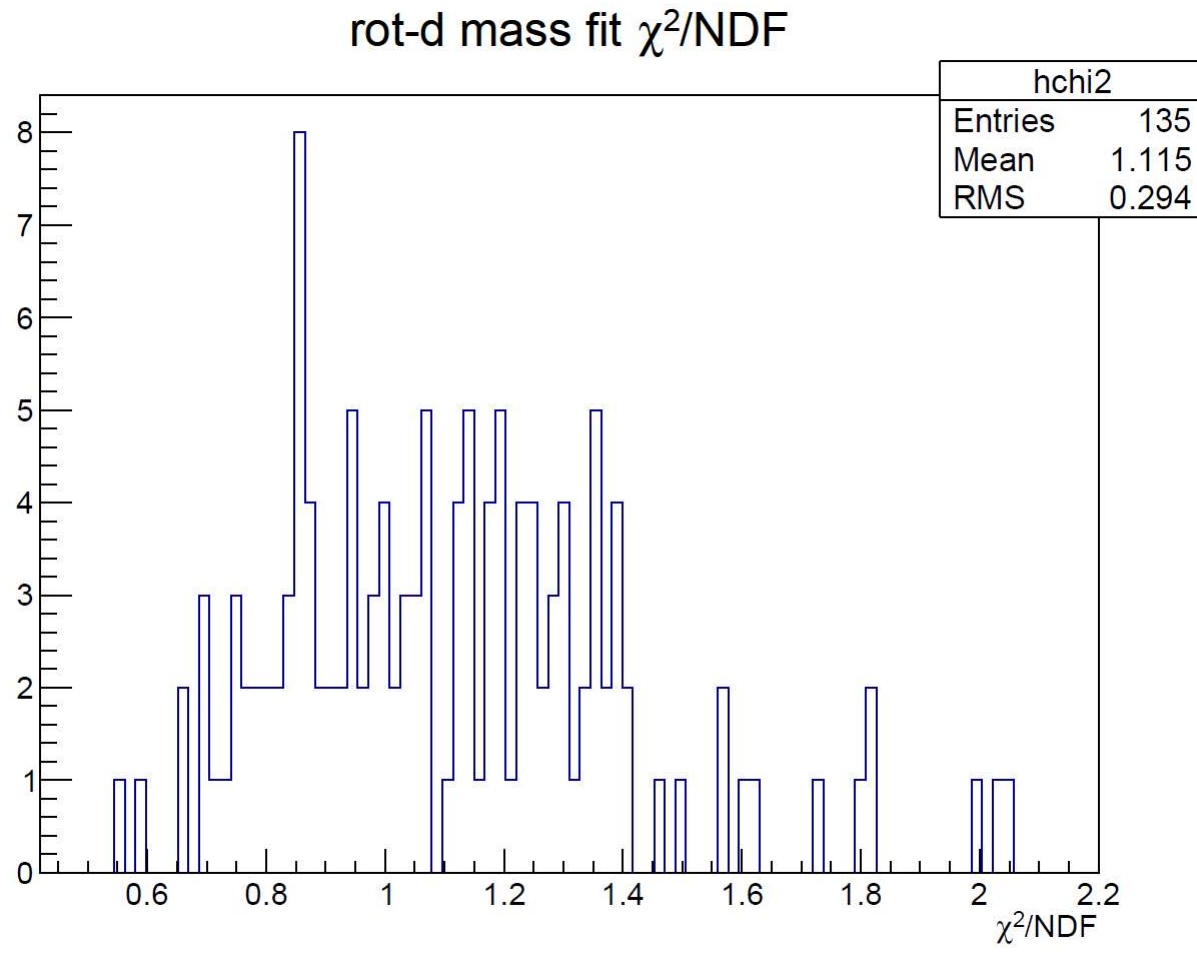
Rotated mass fitting coarse bins (0.1 or 0.2 deg, silicon. w/o tran.)



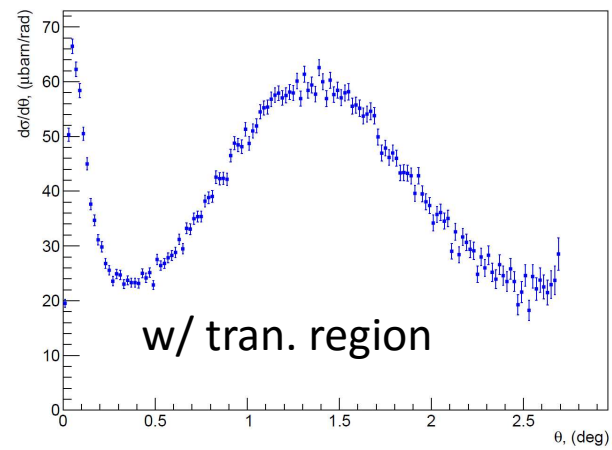
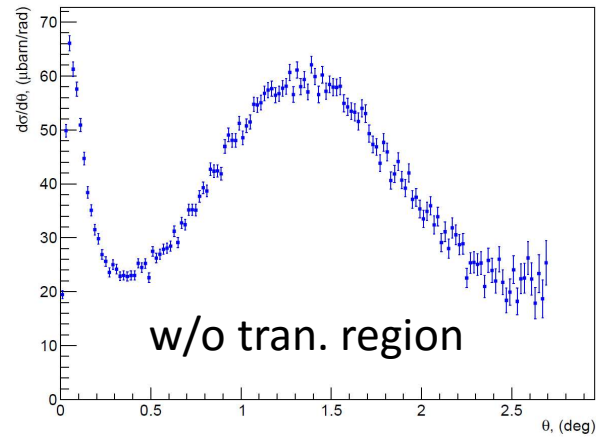
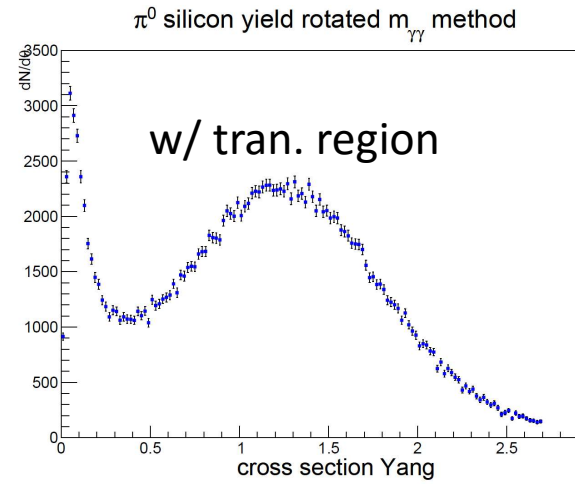
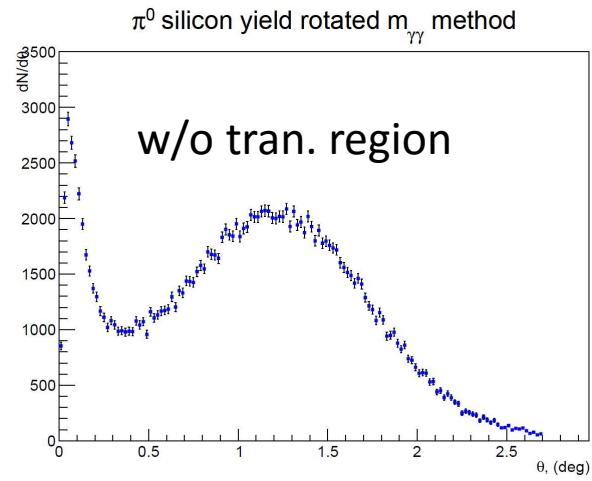
Rotated mass fitting final bins (0.02 deg, silicon, w/o tran.)



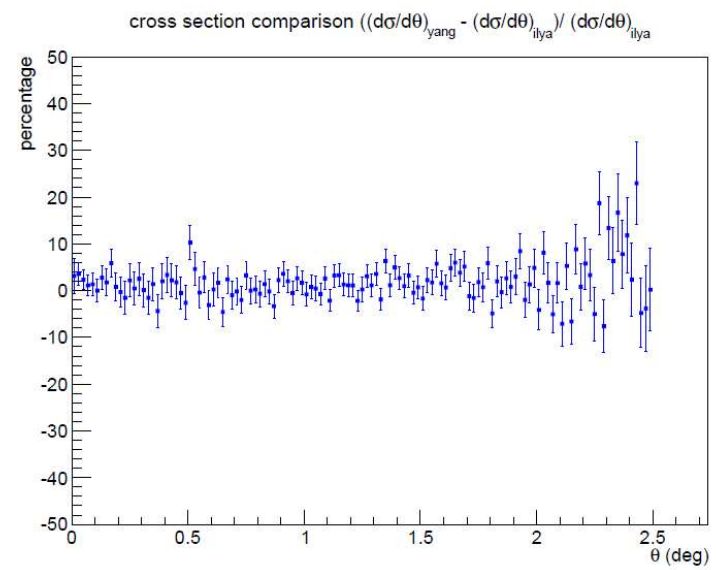
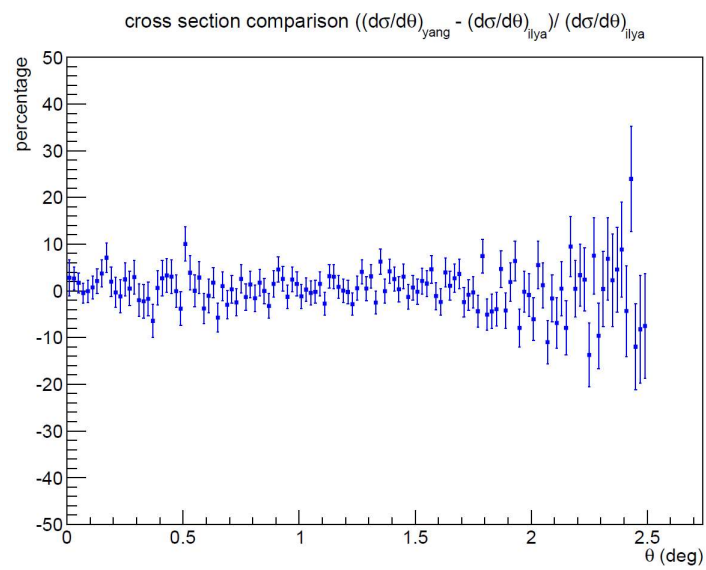
Fitting χ^2/NDF distribution



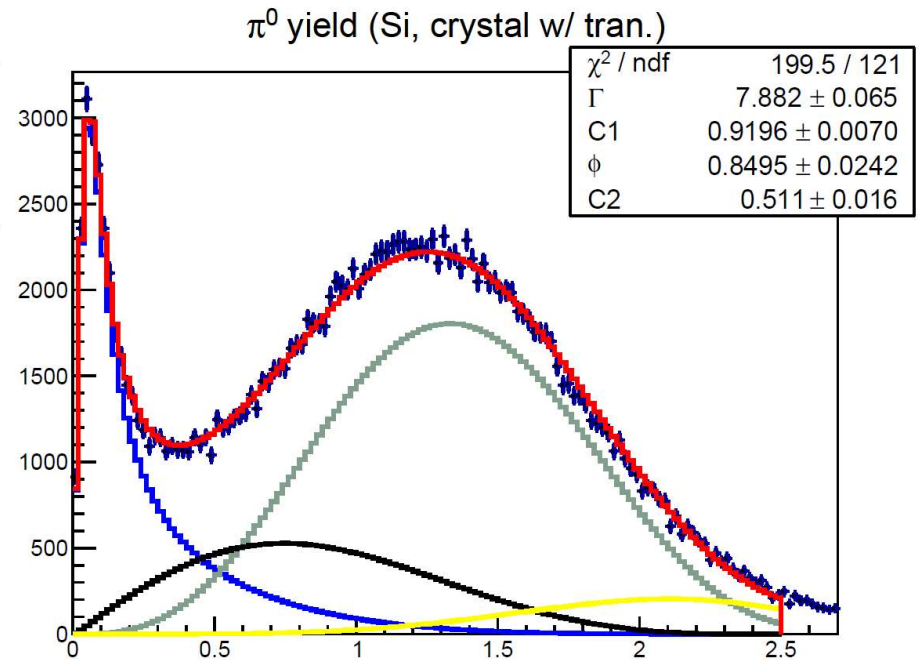
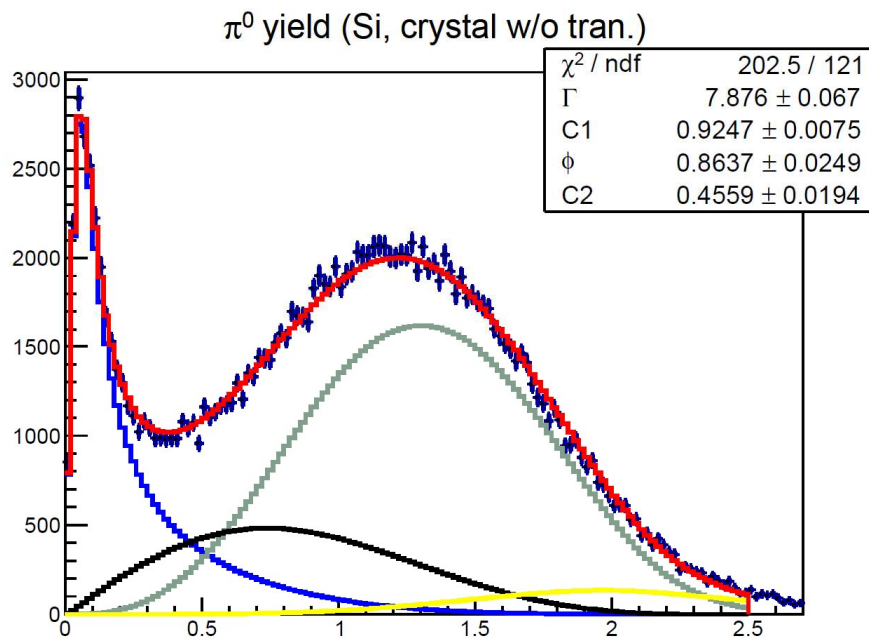
Yields and cross sections



Compare to Lingling/Ilya's cross section



Decay width fitting



Summary

- Previous using M.C. shape to fit signal

Silicon	Γ eV	C1	φ	C2	χ^2 /NDF
w/o tran.(need correction)	7.883 ± 0.067	0.925 ± 0.008	0.857 ± 0.025	0.462 ± 0.020	1.617
w/ tran.(need correction)	7.947 ± 0.065	0.924 ± 0.007	0.852 ± 0.024	0.516 ± 0.016	1.617
Acc sub. w/o tran.	7.918 ± 0.067	0.934 ± 0.007	0.850 ± 0.025	0.438 ± 0.018	1.590
Acc sub. w/ tran.	7.989 ± 0.065	0.926 ± 0.007	0.848 ± 0.024	0.519 ± 0.016	1.635

- Double Gaussian fitting

w/o tran. (need correction)	7.876 ± 0.067	0.925 ± 0.008	0.864 ± 0.025	0.456 ± 0.019	1.674
w/ tran. (need correction)	7.882 ± 0.065	0.920 ± 0.007	0.850 ± 0.024	0.511 ± 0.016	1.649